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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/725,938	12/03/2003	Holger Hoppe	543822002400	4491
25227	7590	02/01/2005	EXAMINER	
MORRISON & FOERSTER LLP 1650 TYSONS BOULEVARD SUITE 300 MCLEAN, VA 22102				KOBERT, RUSSELL MARC
ART UNIT		PAPER NUMBER		
		2829		

DATE MAILED: 02/01/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

<b>Office Action Summary</b>	Application No.	Applicant(s)
	10/725,938	HOPPE, HOLGER <i>CHW</i>
	Examiner	Art Unit
	Russell M Kober	2829

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM  
THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

#### Status

1) Responsive to communication(s) filed on 03 December 2003.  
 2a) This action is FINAL.                            2b) This action is non-final.  
 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

#### Disposition of Claims

4) Claim(s) 1-14 is/are pending in the application.  
 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.  
 5) Claim(s) \_\_\_\_\_ is/are allowed.  
 6) Claim(s) 1-14 is/are rejected.  
 7) Claim(s) \_\_\_\_\_ is/are objected to.  
 8) Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

#### Application Papers

9) The specification is objected to by the Examiner.  
 10) The drawing(s) filed on \_\_\_\_\_ is/are: a) accepted or b) objected to by the Examiner.  
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).  
 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

#### Priority under 35 U.S.C. § 119

12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  
 a) All    b) Some \* c) None of:  
 1. Certified copies of the priority documents have been received.  
 2. Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.  
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

#### Attachment(s)

1) Notice of References Cited (PTO-892)  
 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  
 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
 Paper No(s)/Mail Date 2-11-04

4) Interview Summary (PTO-413)  
 Paper No(s)/Mail Date. \_\_\_\_\_  
 5) Notice of Informal Patent Application (PTO-152)  
 6) Other: \_\_\_\_\_

1. The oath or declaration is defective. A new oath or declaration in compliance with 37 CFR 1.67(a) identifying this application by application number and filing date is required. See MPEP §§ 602.01 and 602.02.

The oath or declaration is defective because:

It fails to identify the Priority Document to which Priority is claimed.

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

3. Claims 1-14 are rejected under 35 U.S.C. 102(b) as being clearly anticipated by Kang (6323669).

4. Claims 1-14 are rejected under 35 U.S.C. 102(b) as being anticipated by Ohba (6323666).

Ohba anticipates a testing method for testing contacting between a semiconductor device and a carrier, comprising loading the carrier with the semiconductor device, such that contacting between the carrier and the semiconductor device is tested immediately after the loading of the carrier with the semiconductor device (col 4, ln 38-47, 63-67); as recited in claim 1.

As to claim 2, connecting the carrier to a testing apparatus is anticipated by Ohba (col 2, In 6-10).

As to claim 3, having the carrier is connected to the testing apparatus and the carrier subsequently loaded with the semiconductor device is considered an inherent function within the operable scope of Ohba.

As to claim 4, Ohba anticipates the carrier being loaded at a carrier loading station and contacting between the carrier and the semiconductor device is tested before the carrier is transported to a further station (see SUMMARY OF THE INVENTION).

As to claim 5, having the contacting between the carrier and the semiconductor device tested by the testing apparatus is considered an inherent function within the operable scope of Ohba.

As to claim 6, the testing apparatus being configured such that it tests the contacting between the carrier and the semiconductor device without functioning of the semiconductor device is considered an inherent function within the operable scope of Ohba (col 3, In 6-10).

As to claim 7, performing the contacting between the carrier and the semiconductor device being tested within 2 seconds after loading of the carrier with the semiconductor device is considered an inherent function within the operable ranges of Ohba.

Moreover, the limitations of claims 8-11 are considered inherent in the apparatus of Ohba and within the normal range of operating the apparatus of Ohba.

As to claim 12, Ohba anticipates a testing system for testing contacting between a semiconductor device and a carrier, comprising a testing apparatus to which a carrier

can be connected, and which is configured such that contacting between the carrier and the semiconductor device is tested by the testing device immediately after loading of the carrier with a semiconductor device (col 4, ln 38-47, 63-67).

As to claim 13, having the test apparatus performing the test after a signal is output by a loading device, the signal indicating that the carrier was loaded with the semiconductor device is considered an inherent part of the operation of Ohba (col 4, ln 19-42).

As to claim 14, the test system further comprising a testing apparatus, the testing apparatus being configured such that contacting between the carrier and the semiconductor device is tested immediately after loading of the carrier with the semiconductor device is anticipated by Ohba (col 4, ln 38-47, 63-67).

5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Onishi et al (5788084) shows a test system for inspecting the contact characteristics of the contact pins of sockets.

Yoshioka (6380492) shows a contact film and mounting structure for use with BGA type devices whereby electrical contact with the solder balls can be verified.

6. A shortened statutory period for response to this action is set to expire three month(s) from the date of this letter. Failure to respond within the period for response will cause the application to become abandoned. 35 U.S.C. 133

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Russell Kobert whose telephone number is (571) 272-1963. The Examiner's Supervisor, Nestor R. Ramirez, can be reached at (571) 272-2034. For an automated menu of Tech Center 2800 phone numbers call (571) 272-2800.



Russell M. Kobert  
Patent Examiner  
Group Art Unit 2829  
January 28, 2005



VINH NGUYEN  
PRIMARY EXAMINER

A.U. 2829  
01/31/05